

SMD Type

Transistors

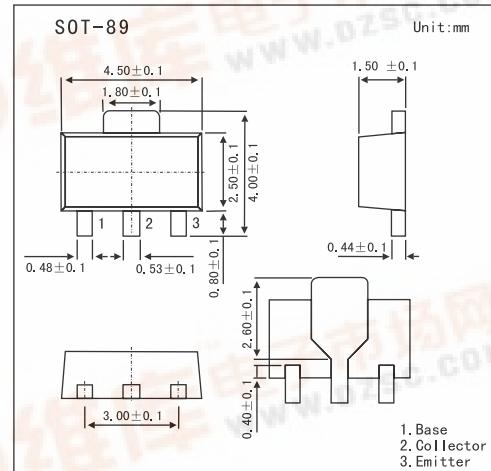
NPN Epitaxial Planar Silicon Transistor

2SC4390



■ Features

- Adoption of MBIT process.
- High DC current gain ($hFE=800$ to 3200).
- Large current capacity ($I_C=2A$).
- Low collector-to-emitter saturation voltage ($V_{CE(sat)} \leq 0.3V$).
- High V_{EB0} ($V_{EB0} \geq 15V$).



■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Collector-base voltage	V_{CBO}	20	V
Collector-emitter voltage	V_{CEO}	10	V
Emitter-base voltage	V_{EB0}	15	V
Collector current	I_C	2	A
Collector current (pulse)	I_{CP}	4	A
Base current	I_B	0.4	A
Collector dissipation	P_C	500	mW
Junction temperature	T_J	150	°C
Storage temperature	T_{stg}	-55 to +150	°C

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■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Collector cutoff current	I _{CBO}	V _{CB} = 15V, I _E =0			0.1	μA
Emitter cutoff current	I _{EB0}	V _{EB} = 10V, I _C =0			0.1	μA
DC current gain	h _{FE}	V _{CE} =2V , I _C = 500mA	800	1500	3200	
Gain bandwidth product	f _T	V _{CE} = 10V , I _C = 50mA		260		MHz
Output capacitance	C _{ob}	V _{CB} = 10V , f = 1.0MHz		280		pF
Collector-emitter saturation voltage	V _{CESat}	I _C = 1 A , I _B = 20mA		0.11	0.5	V
Base-emitter saturation voltage	V _{BESat}	I _C = 1 A , I _B = 20mA		0.87	1.2	V
Collector-base breakdown voltage	V _{(BR)CBO}	I _C = 10μA , I _E = 0	20			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C = 1mA , R _{BE} = ∞	10			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E = 10μA , I _C = 0	15			V
Turn-on time	t _{on}	Switching Time Test Circuit PW = 20μs DC ≤ 1%		0.13		μs
Storage time	t _{sig}			0.8		μs
Fall time	t _f			0.1		μs

